

# MBN1800E17DD

Silicon N-channel IGBT

## FEATURES

- \* High speed, low loss IGBT module due to LiPT Trench Technology
- \* Low noise due to ultra soft fast recovery diode. (U-SFD)
- \* High reverse recovery capability (HiRC)
- \* High thermal fatigue durability. ( $\Delta T_c=70^\circ\text{C}$ ,  $N>30,000$ cycles)

## ABSOLUTE MAXIMUM RATINGS ( $T_c=25^\circ\text{C}$ )

Item	Symbol	Unit	MBN1800E17DD
Collector Emitter Voltage	$V_{CES}$	V	1,700
Gate Emitter Voltage	$V_{GES}$	V	$\pm 20$
Collector Current	DC	$I_C$	1,800
	1ms	$I_{Cp}$	3,600
Forward Current	DC	$I_F$	1,800
	1ms	$I_{FM}$	3,600
Junction Temperature	$T_j$	$^\circ\text{C}$	-40 ~ +125
Storage Temperature	$T_{stg}$	$^\circ\text{C}$	-40 ~ +125
Isolation Voltage	$V_{ISO}$	$V_{RMS}$	4,000 (AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/15 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value  $1.8\pm 0.2 / 15^{+0}_{-3}$ N·m(2) Recommended Value  $5.5\pm 0.5$ N·m

## ELECTRIC CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	$I_{CES}$	mA	-	-	12	$V_{CE}=1,700\text{V}$ , $V_{GE}=0\text{V}$ , $T_j=25^\circ\text{C}$
			-	15	50	$V_{CE}=1,700\text{V}$ , $V_{GE}=0\text{V}$ , $T_j=125^\circ\text{C}$
Gate Emitter Leakage Current	$I_{GES}$	nA	-500	-	+500	$V_{GE}=\pm 20\text{V}$ , $V_{CE}=0\text{V}$ , $T_j=25^\circ\text{C}$
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	V	-	2.2	-	$I_C=1,800\text{A}$ , $V_{GE}=15\text{V}$ , $T_j=25^\circ\text{C}$
			-	2.7	3.3	$I_C=1,800\text{A}$ , $V_{GE}=15\text{V}$ , $T_j=125^\circ\text{C}$
Gate Emitter Threshold Voltage	$V_{GE(To)}$	V	5.0	6.5	8.0	$V_{CE}=10\text{V}$ , $I_C=180\text{mA}$ , $T_j=25^\circ\text{C}$
Input Capacitance	$C_{ies}$	nF	-	150	-	$V_{CE}=10\text{V}$ , $V_{GE}=0\text{V}$ , $f=100\text{kHz}$ , $T_j=25^\circ\text{C}$
Gate Charge	$Q_G$	$\mu\text{C}$	-	12	-	$V_{GE}=\pm 15\text{V}$ , $V_{CC}=900\text{V}$ , $I_C=1,800\text{A}$
Internal Gate Resistance (Tentative)	$R_{ge(int)}$	$\Omega$	-	0.9	-	$V_{CE}=10\text{V}$ , $V_{GE}=0\text{V}$ , $f=100\text{kHz}$ , $T_j=25^\circ\text{C}$
Switching Times	Rise Time	$t_r$	-	0.8	1.6	$V_{CC}=900\text{V}$ , $I_C=1,800\text{A}$
	Turn On Time	$t_{on}$	-	1.3	2.6	$L=55\text{nH}$ , $C_{GE}=180\text{nF}$ <sup>(3)</sup>
	Fall Time	$t_f$	-	0.2	0.4	$R_G=1.5\Omega$ <sup>(3)</sup>
	Turn Off Time	$t_{off}$	-	1.5	3.0	$V_{GE}=\pm 15\text{V}$ , $T_j=125^\circ\text{C}$
Peak Forward Voltage Drop	$V_{FM}$	V	-	1.6	-	$I_F=1,800\text{A}$ , $V_{GE}=0\text{V}$ , $T_j=25^\circ\text{C}$
			-	1.7	2.3	$I_F=1,800\text{A}$ , $V_{GE}=0\text{V}$ , $T_j=125^\circ\text{C}$
Reverse Recovery Time	$t_{rr}$	$\mu\text{s}$	-	0.7	1.4	
Turn On Loss	$E_{on(10\%)}$	J/P	-	0.65	1.0	
	$E_{on(Full)}$	J/P	-	0.7	(1.05)	$V_{CC}=900\text{V}$ , $I_C=1,800\text{A}$
Turn Off Loss	$E_{off(10\%)}$	J/P	-	0.58	0.9	$L=55\text{nH}$ , $C_{GE}=180\text{nF}$ <sup>(3)</sup>
	$E_{off(Full)}$	J/P	-	0.65	(1.05)	$R_G=1.5\Omega$ <sup>(3)</sup>
Reverse Recovery Loss	$E_{rr(10\%)}$	J/P	-	0.68	1.1	$V_{GE}=\pm 15\text{V}$ , $T_j=125^\circ\text{C}$
	$E_{rr(Full)}$	J/P	-	0.8	(1.2)	
Reverse Recovery Peak Current	$I_{RRM}$	A	-	1,800	-	
RBSOA	$I_C$	A	3,600	-	-	$V_{CC}=1,000\text{V}$ , $L=55\text{nH}$ , $C_{GE}=180\text{nF}$ <sup>(3)</sup>
Recovery SOA	$I_F$	A	3,600	-	-	$R_G=1.5\Omega$ <sup>(3)</sup> $V_{GE}=\pm 15\text{V}$ , $T_j=125^\circ\text{C}$
$I^2t$ value	$I^2t$	$\text{kA}^2\text{s}$	-	1,000	-	$T_{j,start}=125^\circ\text{C}$ , 10ms, $V_R=0\text{V}$
Partial Discharge Extinction Voltage	$V_{PDoff}$	$V_{RMS}$	1.3	-	-	$Q=10\text{pC}$ , 50Hz,

Notes : (3)  $R_G$  and  $C_{GE}$  value is the test condition's value for evaluation of the switching times, not recommended value.Please, determine the suitable  $R_G$  and  $C_{GE}$  value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

\* Please contact our representatives at order.

\* For improvement, specifications are subject to change without notice.

\* For actual application, please confirm this spec sheet is the newest revision.

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## THERMAL CHARACTERISTICS

Item		Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Thermal Resistance	IGBT	Rth(j-c)	K/W	-	-	0.013	Junction to case
	FWD	Rth(j-c)		-	-	0.015	
Contact Thermal Impedance		Rth(c-f)	K/W	-	0.006	-	Case to fin. Thermal grease applied. Thickness 100μm, Thermal conductivity of grease: 1W/mK

## MODULE MECHANICAL CHARACTERISTICS

Item		Unit	Characteristics	Conditions
Weight		g	1,300	
Cree page Distance	Between terminal	mm	22	
	Terminal-Base	mm	19.5	
Clearance Distance	Between terminal	mm	35	
	Terminal-Base	mm	35	
Stray inductance in module	LS(CM-EM)	nH	12	Collector-main to Emitter-main
	LS(ES-EM)		49	Emitter-sense to Emitter-main
	LS(CM-CS)		56	Collector-main to Collector sense
Terminal Resistance	R <sub>Terminal</sub>	mΩ	0.09	Collector-main to Emitter-main
Comparative Tracking Index (CTI)			600	
Module base plate Material			Al-SiC	
Baseplate Thickness		mm	5	
Insulation Material			AlN	
Terminal Surface treatment			Ni plating	
Case Material			Poly-Phenilene Sulfide	
Fire and Smoke Category			I2 / F3	NFF 16-102

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## DEFINITION OF TEST CIRCUIT

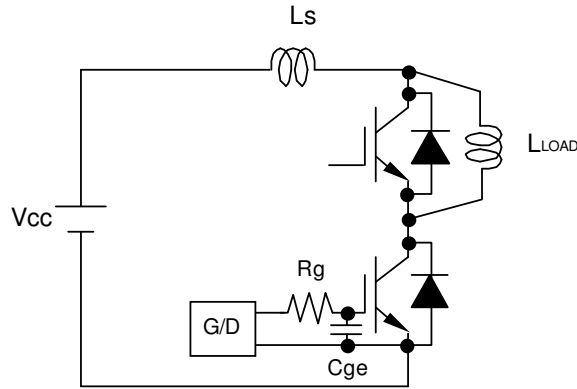


Fig.1 Switching test circuit

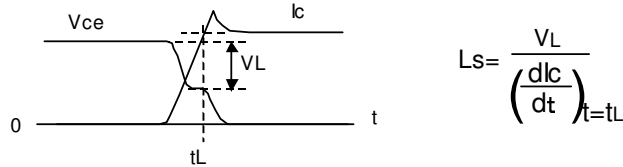


Fig.2 Definition of stray inductance

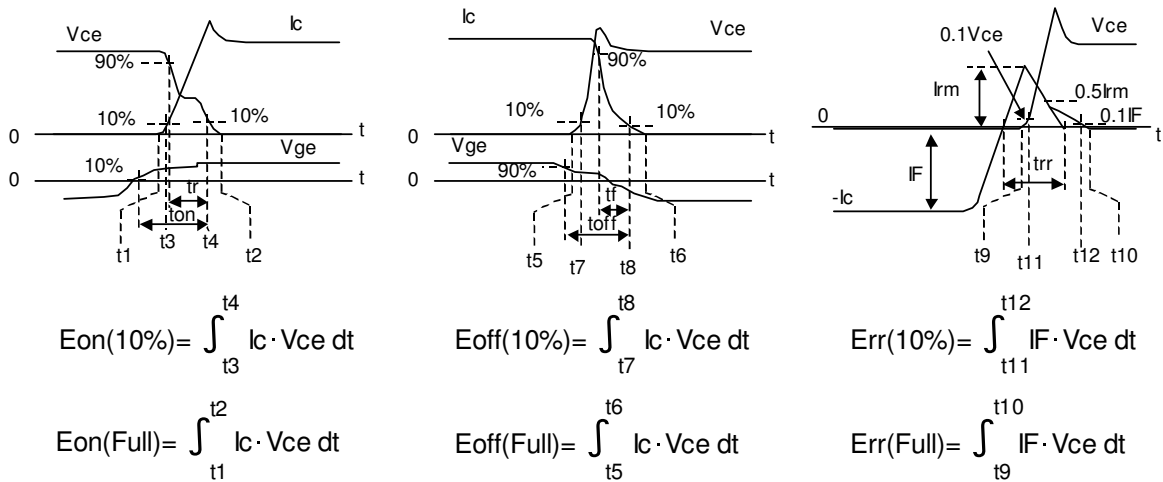
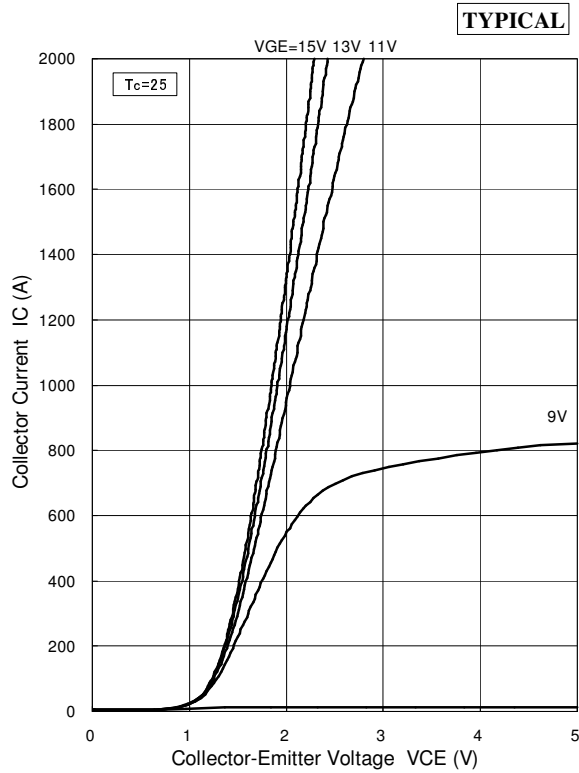


Fig.3 Definition of switching loss

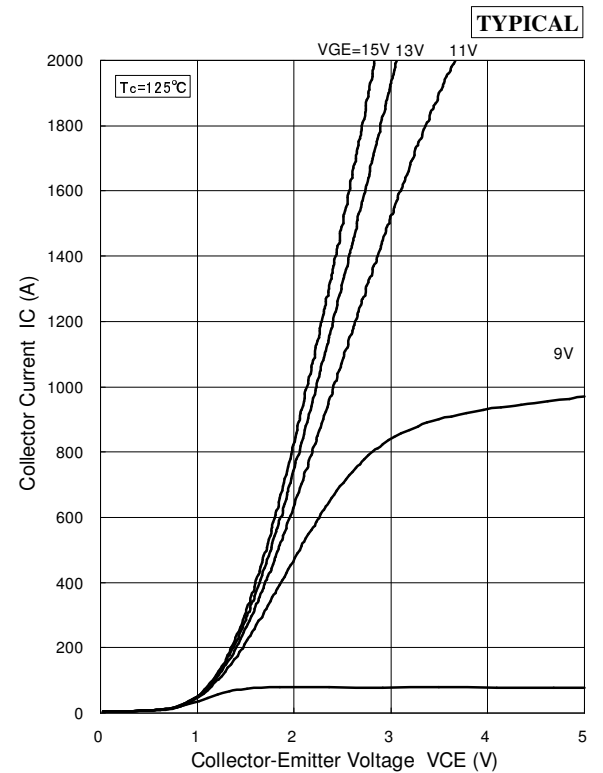
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## CHARACTERISTICS CURVE

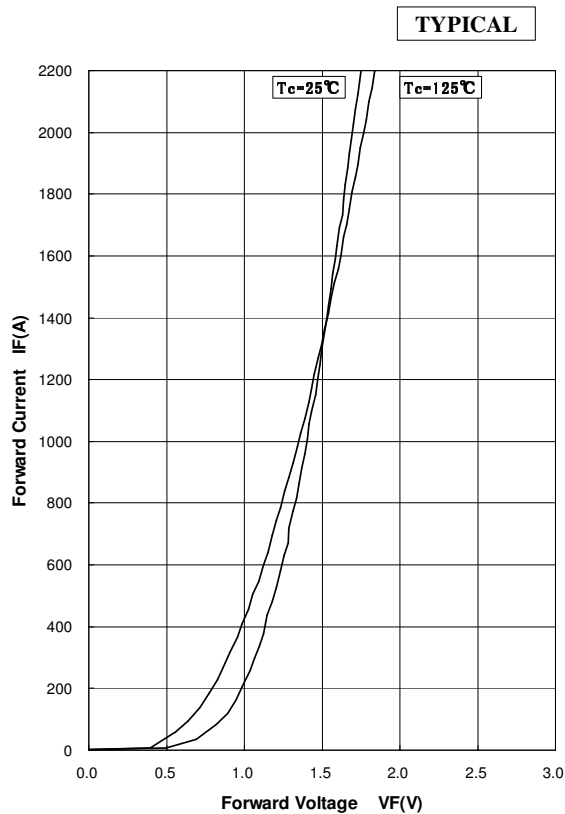
### STATIC CHARACTERISTICS



Collector Current vs. Collector to Emitter Voltage



Collector Current vs. Collector to Emitter Voltage

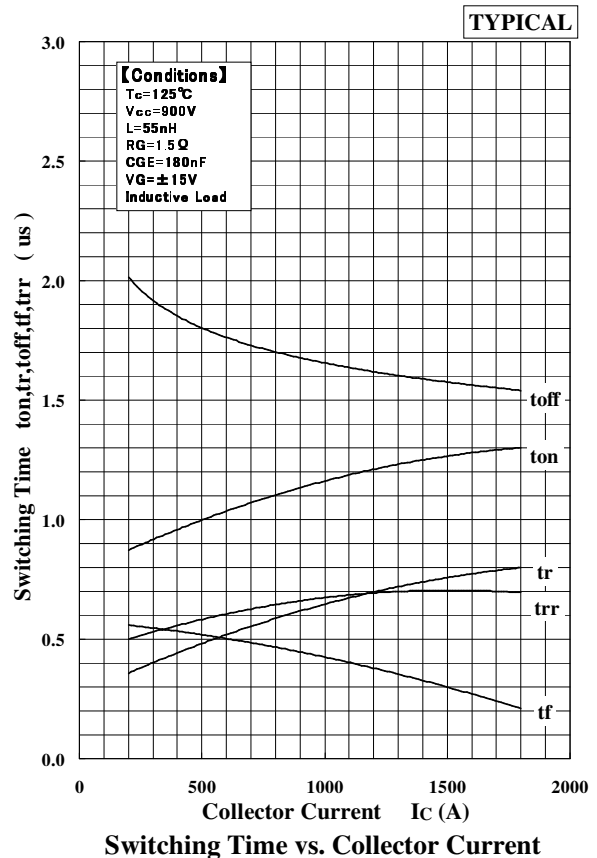
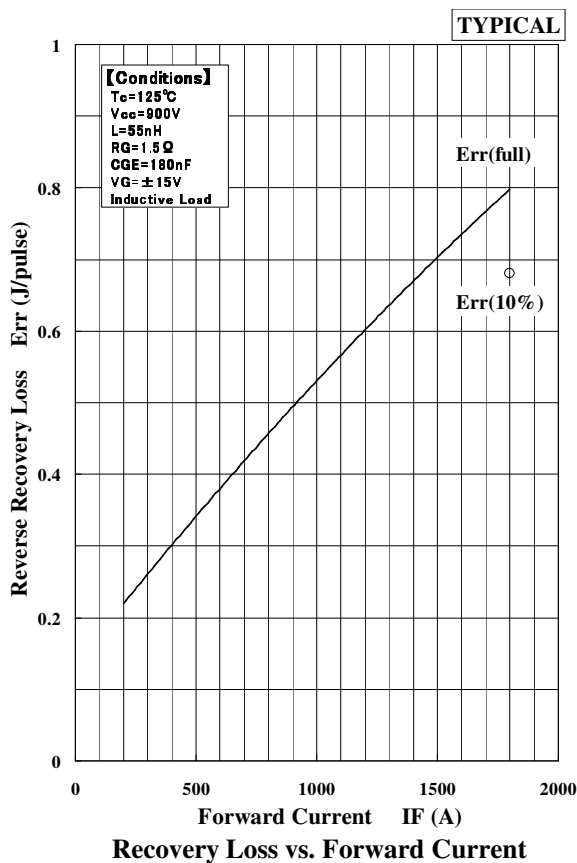
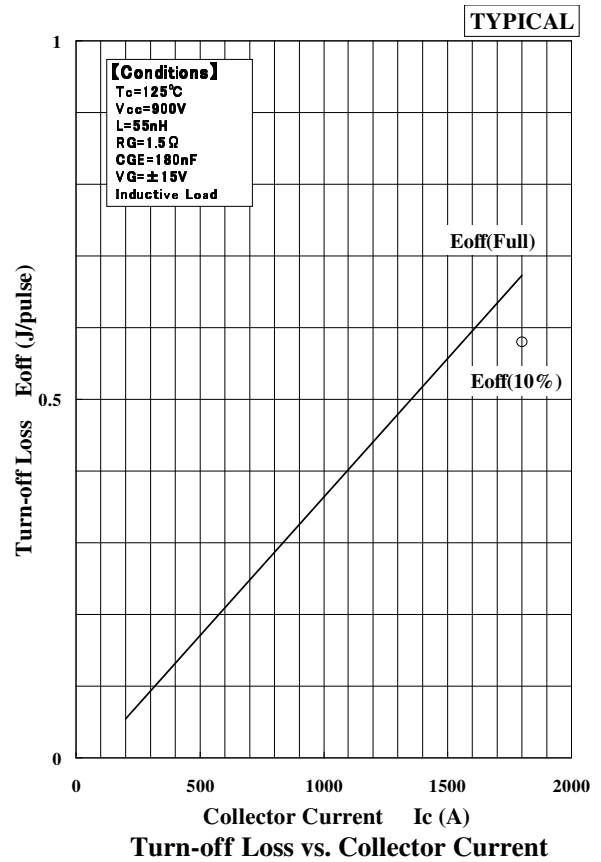
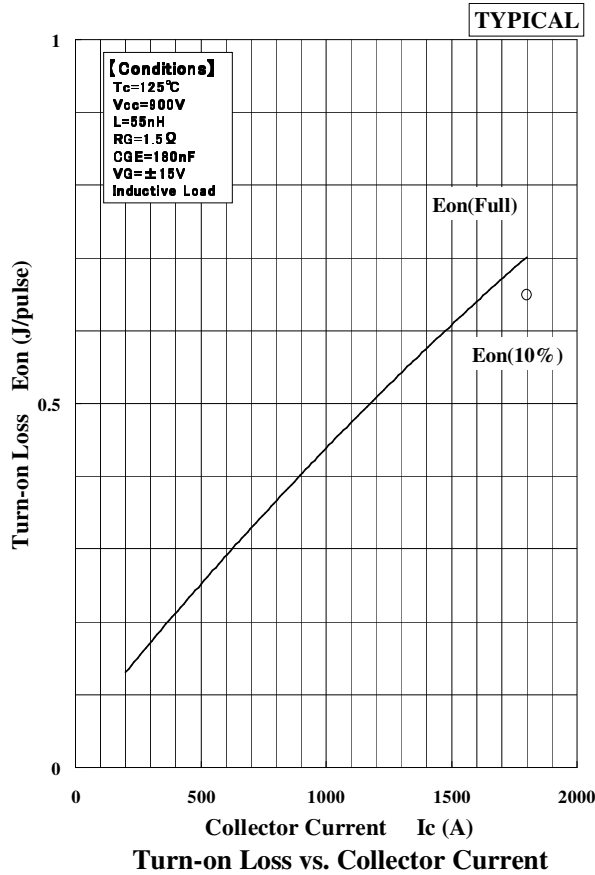


Forward Voltage of free-wheeling diode

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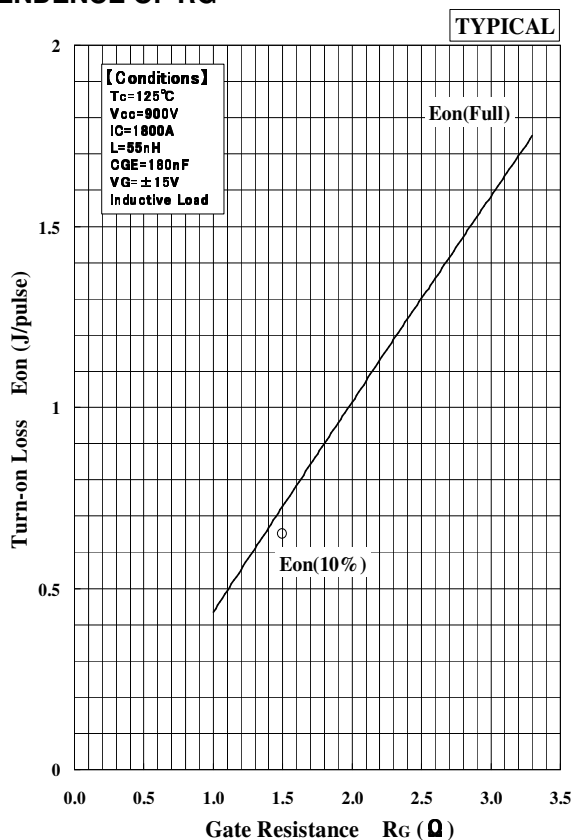
## DYNAMIC CHARACTERISTICS

### DEPENDENCE OF CURRENT

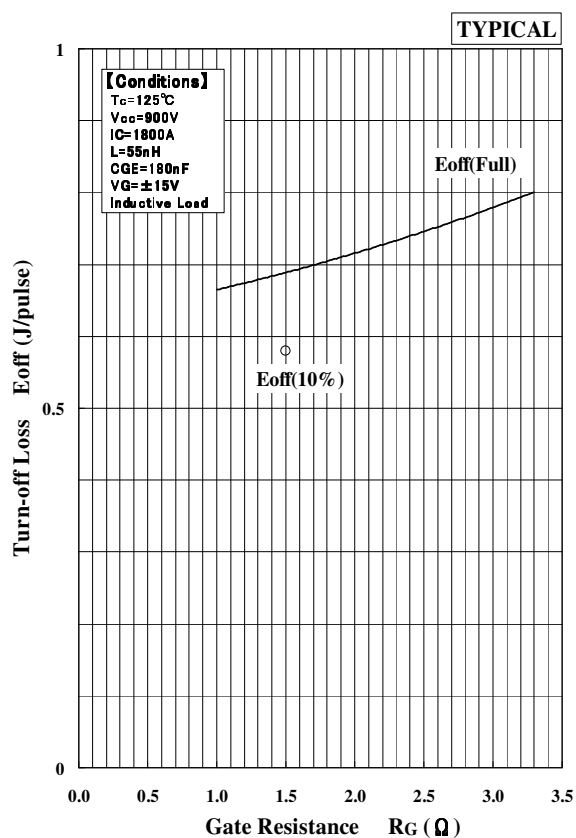


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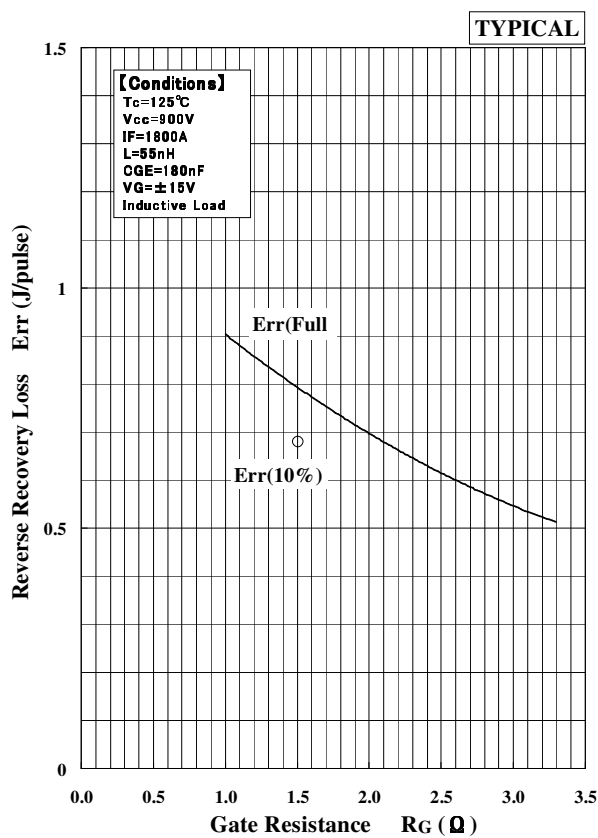
## DEPENDENCE OF RG



Turn-on Loss vs. Gate Resistance



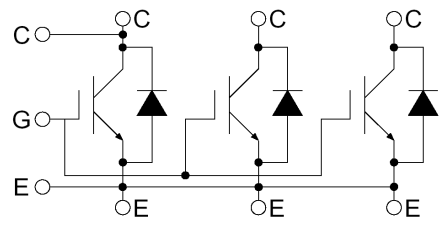
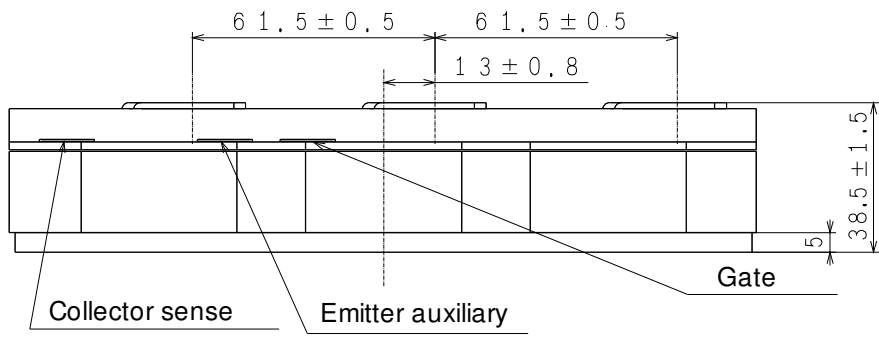
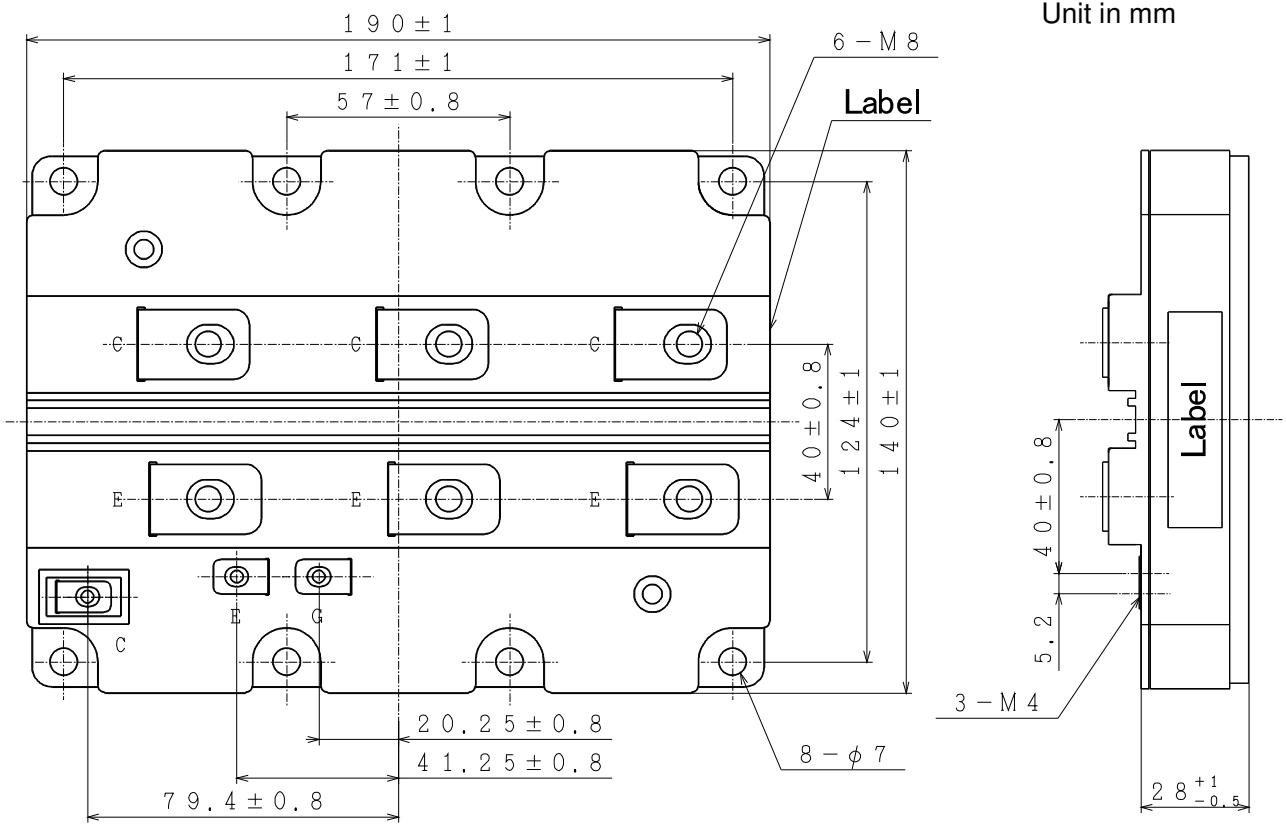
Turn-off Loss vs. Gate Resistance



Recovery Loss vs. Gate Resistance

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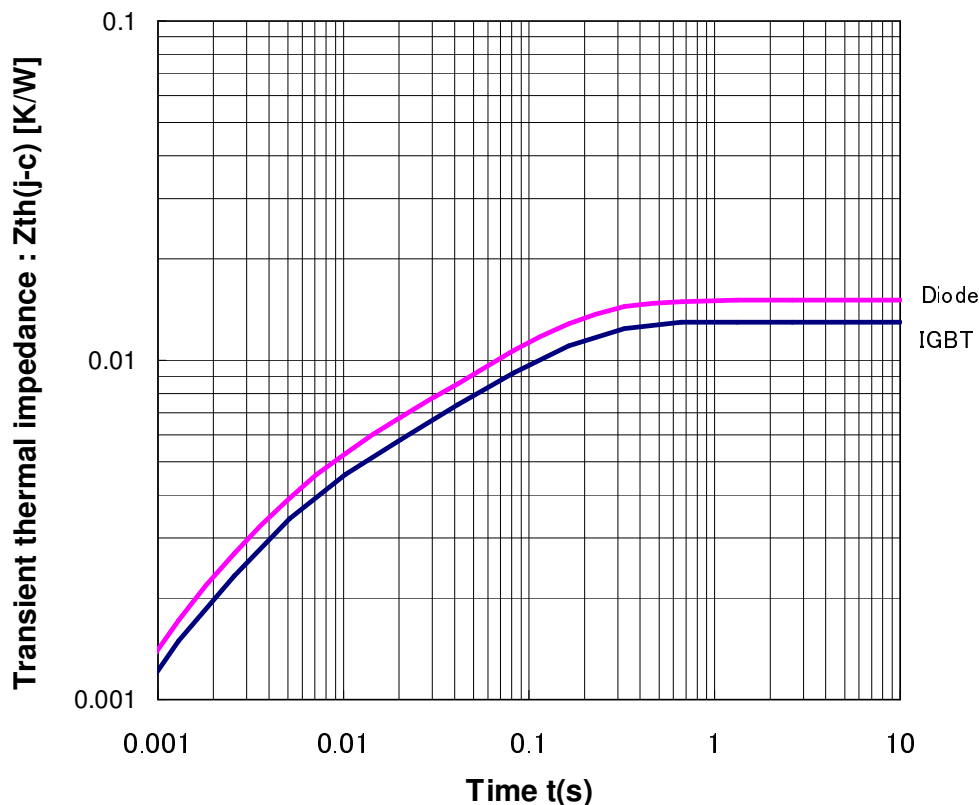
## PACKAGE OUTLINE DRAWING



CIRCUIT DIAGRAM

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**TRANSIENT THERMAL IMPEDANCE**



*Transient Thermal Impedance Curve (Maximum Value)*

**Curve approximation model**

Following expressions approximates the transient thermal impedance curves.

Please note that the expressions are the curve fitted value, and there is no physical meaning in this expression. The expressions are applicable under following condition only.

- Condition 1: Time is more than t (1)/e
- Condition 2: No heat sink model is considered.

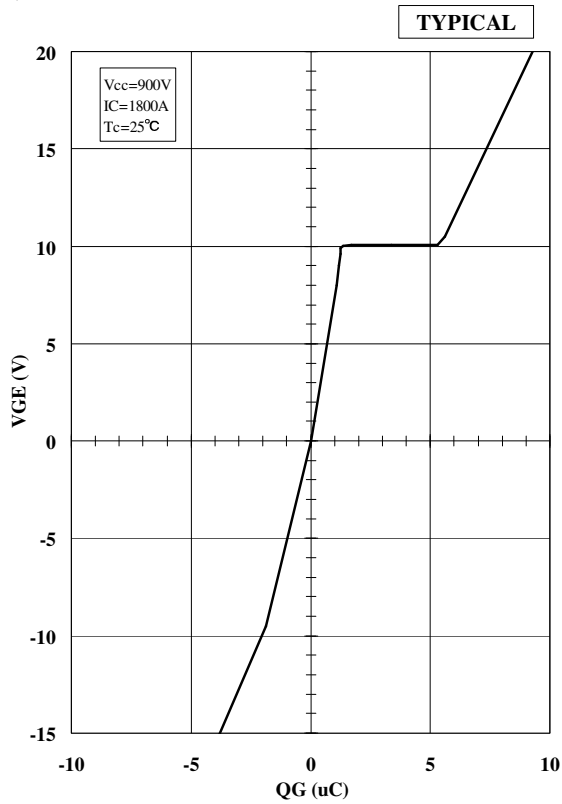
$$Z_{th}(j-c) = \sum Z_{th}[n] * (1 - \exp(-t / \tau_{th}[n])) \quad (1)$$

n	1	2	3	4	5	6	7	Unit
$\tau_{th}[n]$	0.10	0.01	0.003	0.001	0.0003	0.0001	0.00003	sec
$Z_{th}[n,IGBT]$	7.958E-03	2.906E-03	1.177E-03	7.921E-04	9.798E-06	1.406E-05	4.434E-06	K/W
$Z_{th}[n,Diode]$	9.852E-03	2.171E-03	2.178E-03	7.765E-04	1.000E-07	4.289E-07	1.279E-05	K/W



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## QG-VGE Curve



QG-VGE curve

## Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder

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## HITACHI POWER SEMICONDUCTORS

### Notices

1. The information given herein, including the specifications and dimensions, is subject to change without prior notice to improve product characteristics. Before ordering, purchasers are advised to contact Hitachi sales department for the latest version of this data sheets.
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